

2004 IEEE Instrumentation and Measurement Technology Conference  
Como, Italy

Tuesday, 18 May 2004

Morning 08.30AM-10.30AM	registration					
	9.30AM					
<b>KeyNote</b>						
Coffee Break						
Morning 11.00AM-01.00PM	TB1 Chemical measurements 1 4141	TB2 Signal processing 1 4072	TB3 ss Radio-frequency dielectric properties of materials and applications 4090	TB4 Smart sensors systems 4566	TB5 ss Traceability issues in distributed and software-based measurement systems 4442	TB6 Materials 1 4015
	4228	4134	4060	4611	4443	4225
	4101	4467	4329	4152	4066	4052
	4439	4402	4504	4145	4399	4213
				4185	4320	
Lunch						
Afternoon 02.00PM-04.00PM	<b>N</b> National Instruments Seminar	TD2 Signal Processing 2 4424	TD3 ss Microwave measurements and instrumentation 1 4503	TD4 Position measurements 1 4099	TD5 Uncertainty 4397	TD6 Measurement in Telecommunications 1 4496
	4210	4493	4082	4498	4283	
	4211	4605	4245	4065	4325	
	4247	4435	4438	4256	4078	
	4073	4237	4177	4489	4188	
Coffee Break						
Afternoon 04.30PM-06.30PM	TE1 Robotics 4606	TE2 Signal processing 3 4178	TE3 ss Microwave measurements and instrumentation 2 4520	TE4 Mechanical quantities 4279	TE5 Calibration 4243	TE6 Measurement in Telecommunications 2 4603
	4534	4151	4369	4056	4002	4378
	4027	4005	4416	4047	4107	4459
	4600	4272	4352	4086	4001	4458
	4428		4229	4292	4106	4505

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Wednesday, 19 May 2004						
Morning 08.30AM-10.30AM	WA1 Digital imaging techniques 2	WA2 Detectors for nuclear and particle physics	WA3 Electrical measurements 1	WA4 Analog-to-Digital Converters 3	WA5 Medical instrumentation	WA6 Microwave-based measurements
	4500	4587	4197	4164	4469	4298
	4481	4548	4097	4059	4409	4306
	4354	4554	4513	4166	4161	
	4382	4576	4053	4604	4267	
				4451	4255	
Coffee Break						
Morning 11.00AM-01.00PM	WB1 Digital imaging techniques 3	WB2 Detectors for nuclear and particle physics: Vertex	WB3 Magnetic measurements 1	WB4 Analog-to-Digital Converters 4	WB5 Biological measurements	WB6 Sensor array
	4552	4547	4321	4064	4108	4536
	4363	4544	4289	4462	4249	4528
	4170	4518	4404	4150	4077	4537
	4196	4575	4117		4457	4519
	4084	4570			4158	
Lunch						
Afternoon 02.00PM-04.00PM	WD1 Digital imaging techniques 4	WD2 Detectors for nuclear and particle physics: Tracking and Particle Identification	WD3 Electronic tools for education and training in instrumentation and measurement 2	WD4 Sigma-delta modulators	WD5 Sensor networks: technologies, methodologies, and applications !	WD6 Optical sensors 1
	4280	4588	4230	4307	4465	4300
	4485	4564	4484	4577	4466	4241
	4232	4561	4478	4418	4293	4581
	4431		4491	4336	4140	4242
	4251				4079	4408
Coffee Break						
Afternoon 04.30PM-06.30PM	WE1 Bayesian methods in measurement	WE2 Detectors for nuclear and particle physics: Calorimeters 1	WE3 Electronic tools for education and training in instrumentation and measurement 3	WE4 Signal generators and noise	WE5 Sensor networks: technologies, methodologies, and applications 2	WE6 Optical instrumentation and measurement for industrial applications
	4440	4584	4523	4345	4184	4597
	4127	4562	4441	4526	4456	4432
	4138	4531	4490	4202	4470	4596
	01		4448	4305		4285
			4494			4407

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**Thursday, 20 May 2004**

Morning 08.30AM-10.30AM	HA1  ss Medical measurements and instrumentation 1  4419	HA2  Identification 1  4000	HA3  ss Electric power quality measurements and relevant uncertainty estimation 2  4468	HA4  ss Defect and fault tolerance for dependability: mission-critical measurement systems 2  4601	HA5  Transportation  4582
	4169	4299	4396	4156	4510
	4154	4205	4476	4136	
	4023	4017	4393	4172	
	4100	4092	4125	4071	
Coffee Break					
Morning 11.00AM-01.00PM	HB1  ss Medical measurements and instrumentation 2  4054	HB2  Identification 2  4008	HB3  ss Electric power quality measurements and relevant uncertainty estimation 3  4539	HB4  ss Defect and fault tolerance for dependability: mission-critical measurement systems 3  4055	HB5  Measurements for industrial applications 1  4168
	4319	4350	4492	4104	4003
	4098	4473	4514	4238	4277
	4464	4091	4522	4040	4058
	4033	4311			4239
Lunch					
Afternoon 02.00PM-04.00PM	HD1  ss Optical instrumentation and measurement technology for biomedical application  4146	HD2  ss Instrumentation and measurements for nanotechnologies  4461	HD3  Power quality  4515	HD4  ss System-on-chip integrated circuits for instrumentation and measurement systems: design and test 2  4444	HD5  Machine testing  4264
	4261	4263	4334	4463	4265
	4499	4367	4266	4475	4609
	4502	4410		4488	
				4474	
Coffee Break					
Afternoon 04.30PM-06.30PM	HE1  Signal and image processing for medical applications  4114	HE2  Environmental Monitoring 3  4198	HE3  Power measurements  4103	HE4  Automatic Test Equipment  4342	HE5  Temperature measurement  4102
	4069	4121	4302	4391	4195
	4414	4591	4226	4339	4189
	4364	4400	4429	4203	
		4174	4212		

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registration	8.00AM-	
	9.30AM	
Lunch	08.30AM-01-00PM Morning	02.00PM-06.30PM Afternoon

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Wednesday, 19 May 2004									
WC1	WC2	WC3	WC4	WC5	WC6	WC7	WC8	WC9	WC10
Networks for Monitoring	Signal processing 4	Spectrum analyzers	Electronic tools for education and training in instrumentation and measurement 1	Position measurements 2	Position measurements 3	Kinematics measurements 1	Kinematics measurements 2	Measurement in Telecom	
4147	4282	4098	4081	4293	4029	4167	4030		
4455	4214	4171	4186	4308	4434	4155	4193	4014	
4454	4328	4074	4077	4487	4286	4351	4039	4075	
4248	4051	4144	4144	4511	4163	4233	4235	4183	
4453				4449	4557			4254	
Lunch									
WF1	WF2	WF3	WF4	WF5	WF6	WF7	WF8		
Electrical measurements 2	Magnetic power quality 2	Magnetic measurements	Tomography	Defect and fault tolerance for dependability: mission-critical measurement systems 1	System-on-chip integrated circuits for instrumentation and measurement systems: design and test 1	Circuit Design	Circuits		
4583	4395	4022	4045	4341	4287	4142	4529		
4433	4445	4061	4375	452	4483	4377	4128		
4268	4486	4296	4116	4521	4482	4019	4182		
4259	4516	4113	4208	4038	4509	4527	4533		
			4602		4595	4532	4447		
Morning 08.30AM-01.00PM					Afternoon 02.00PM-06.30PM				

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	08.30AM-01.00PM	Afternoon	02.00PM-06.30PM	
		Lunch		
HC1	HF2	Identification 3	Identification 4	
HC2	HF3			
HC3	HF4			
HC4	HF5			
	HF6			
	HF7			
	HF8			
	HF9			
	HF10			
				Optical sensor 2
				Laser
				Flow measurements 2
				Flow measurements 1
				Measurements for industry
				Measurements for industry
				Measurements for industry
				Environmental monitoring
				Acoustic measurements 1
				Acoustic measurements 2
4574	4580	4333	4338	4368
4569	4590	4326	4135	4148
		4330	4076	4270
			4094	4358
				4437
				4284
				4374
				4043
				4313